

MAX4

High Power Burn-In and Test System

For burning-in and testing high power DUTs such as
microprocessors, DSPs, and logic devices,
which require high current and low voltage



System Features

- Burns-in and tests high-power devices
- Output monitoring gives functional test results for every device during burn-in.
- Device power supplied by 24 individual sources per BIB; reads current for each source
- High-power oven dissipation
- Production capacity with 64 BIB positions
- Engineering/QA configurations with up to 32 independent pattern zones
- Lot control and device protection
- ATS and MAX burn-in board compatible

Signal and Bias Features

- High bias current for DUTs
- 96 independent I/O channels
- Stimulus voltages as low as 0.5V
- Up to 24M pattern depth for BIST and JTAG applications
- 3 separate bias voltages per device

Software Features

- Windows 2000 operation and programming
- Modular test-plan development for ease of programming
- DUT pass/fail BIB map
- Easy interface to sorting BIB unloaders

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